

C2220X103J2TACTU

Aliases (C2220X103J2TAC7800) SMD Comm X8G HT150C Flex, Ceramic, 0.01 uF, 5%, 200 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 2220, 3.5 mm



Click here for the 3D model.

General Information	
Series	SMD Comm X8G HT150C Flex
Style	SMD Chip
Description	SMD, MLCC, High Temperature, Ultra-Stable
Features	High Temperature, Ultra-Stable
RoHS	Yes
Termination	Flexible Termination
Marking	No
AEC-Q200	No
Typical Component Weight	130 mg
Shelf Life	78 Weeks
MSL	1

Dimensions		Specifications
Chip Size	2220	Capacitance
L	5.9mm +/-0.75mm	Measurement C
W	5mm +/-0.4mm	Tolerance
т	1mm +/-0.15mm	Voltage DC
S	3.5mm MIN	Dielectric Withs
В	0.7mm +/-0.35mm	Temperature Ra
		Temp. Coefficie
Packaging Specifications		Capacitance Ch

S	3.5mm MIN	Dielectric Withstand
В	0.7mm +/-0.35mm	Temperature Range
		Temp. Coefficient
Packaging Specifications		Capacitance Change
Packaging	T&R, 180mm, Plastic Tape	Reference to +25°Č a Applied (TCC)
Packaging Quantity	1000	Dissipation Factor

Specifications	
Capacitance	0.01 uF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	5%
Voltage DC	200 VDC
Dielectric Withstanding Voltage	500 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms
Dissipation Factor	0.1% 1 kHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

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